ABSTRACT

A probe has a contact portion at one end and a terminal portion to contact with a circuit board at another end, and includes: a low-high resistance portion formed such that a low-resistance portion made of a first metal is coated with a high-resistance portion made of a second metal and has a higher resistivity than the low-resistance portion ; and a middle-high resistance portion including a middle-resistance portion which is connected to the low-resistance portion in a longitudinal direction of the probe and which is made of a third metal having a lower resistivity than the high-resistance portion and having a higher resistivity than the low-resistance portion , and high-resistance portions provided on both side surfaces in one direction of the middle-resistance portion , and connected to the high-resistance portion of the low-high resistance portion .